

Application/Control No.	Applicant(s)/Patent under Reexamination
10/702,572	CERN, YEHUDA
Examiner	Art Unit

Nam V. Nguyen

2612

SEARCHED				
Class	Subclass	Date	Examiner	
340	310.01	3/6/2007	NN	
340	310.05	3/6/2007	NN	
340	310.07	3/6/2007	NN	
340	506,532	3/6/2007	NN	
375	267	3/6/2007	NN	
375	295	3/6/2007	NN	
375	200	3/6/2007	NN	
324	601	3/6/2007	NN	
455	63	3/6/2007	NN	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
				

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Search East: USPAT; US-PUB; EPO; JPO and Derwent	3/6/2007	NN
Consult with Benjamin Lee	3/7/2007	NN
Search Term: plcs/plc/plcc; electromagnetic radiaion intensity; modem; agc/sensor; frequency band	3/6/2007	NN
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